# 74HC00-Q100; 74HCT00-Q100

# **Quad 2-input NAND gate**

Rev. 1 — 12 July 2012

**Product data sheet** 

# 1. General description

The 74HC00-Q100; 74HCT00-Q100 are high-speed Si-gate CMOS devices that comply with JEDEC standard no. 7A. They are pin compatible with Low-power Schottky TTL (LSTTL).

The 74HC00-Q100; 74HCT00-Q100 provides a quad 2-input NAND function.

This product has been qualified to the Automotive Electronics Council (AEC) standard Q100 (Grade 1) and is suitable for use in automotive applications.

### 2. Features and benefits

- Automotive product qualification in accordance with AEC-Q100 (Grade 1)
  - ◆ Specified from -40 °C to +85 °C and from -40 °C to +125 °C
- Input levels:
  - ◆ For 74HC00-Q100: CMOS level
  - ◆ For 74HCT00-Q100: TTL level
- ESD protection:
  - ◆ MIL-STD-883, method 3015 exceeds 2000 V
  - ◆ HBM JESD22-A114F exceeds 2000 V
  - $\bullet$  MM JESD22-A115-A exceeds 200 V (C = 200 pf, R = 0  $\Omega$ )
- Multiple package options

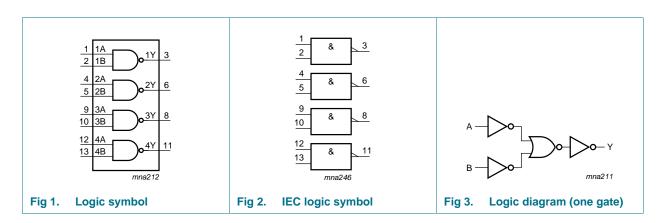


# 3. Ordering information

Table 1. Ordering information

Type number	Package								
	Temperature range	Name	Description	Version					
74HC00D-Q100	–40 °C to +125 °C	SO14	plastic small outline package; 14 leads; body width	SOT108-1					
74HCT00D-Q100			3.9 mm						
74HC00PW-Q100	–40 °C to +125 °C	TSSOP14	plastic thin shrink small outline package; 14 leads;	SOT402-1					
74HCT00PW-Q100			body width 4.4 mm						
74HC00BQ-Q100	–40 °C to +125 °C	DHVQFN14	1	SOT762-1					
74HCT00BQ-Q100			thin quad flat package; no leads; 14 terminals; body $2.5 \times 3 \times 0.85$ mm						

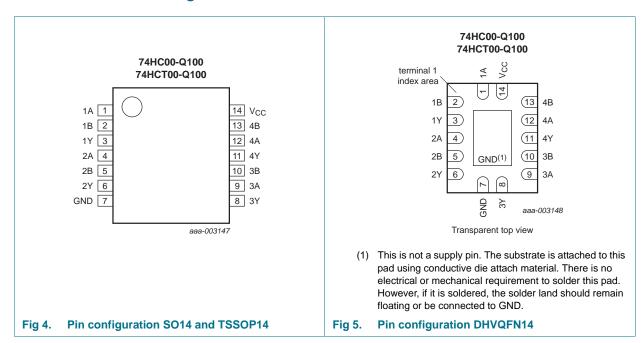
# 4. Functional diagram



Downloaded from Elcodis.com electronic components distributor

# 5. Pinning information

### 5.1 Pinning



### 5.2 Pin description

Table 2. Pin description

Symbol	Pin	Description
1A to 4A	1, 4, 9, 12	data input
1B to 4B	2, 5, 10, 13	data input
1Y to 4Y	3, 6, 8, 11	data output
GND	7	ground (0 V)
V <sub>CC</sub>	14	supply voltage

# 6. Functional description

Table 3. Function table [1]

Input	Output	
nA	nB	nY
L	X	Н
X	L	Н
Н	Н	L

[1] H = HIGH voltage level; L = LOW voltage level; X = don't care.

74HC\_HCT00\_Q100

All information provided in this document is subject to legal disclaimers.

# 7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{CC}$	supply voltage		-0.5	+7	V
I <sub>IK</sub>	input clamping current	$V_I < -0.5 \text{ V or } V_I > V_{CC} + 0.5 \text{ V}$	[1] _	±20	mA
I <sub>OK</sub>	output clamping current	$V_O < -0.5 \text{ V or } V_O > V_{CC} + 0.5 \text{ V}$	[1] _	±20	mA
Io	output current	$-0.5 \text{ V} < \text{V}_{\text{O}} < \text{V}_{\text{CC}} + 0.5 \text{ V}$	-	±25	mA
I <sub>CC</sub>	supply current		-	50	mA
$I_{GND}$	ground current		-50	-	mA
T <sub>stg</sub>	storage temperature		-65	+150	°C
P <sub>tot</sub>	total power dissipation		[2] _	500	mW

<sup>[1]</sup> The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

## 8. Recommended operating conditions

Table 5. Recommended operating conditions

Voltages are referenced to GND (ground = 0 V)

Symbol	Parameter	Conditions	74HC00-Q100			74HCT00-Q100			Unit
			Min	Тур	Max	Min	Тур	Max	
$V_{CC}$	supply voltage		2.0	5.0	6.0	4.5	5.0	5.5	V
VI	input voltage		0	-	$V_{CC}$	0	-	$V_{CC}$	V
Vo	output voltage		0	-	$V_{CC}$	0	-	$V_{CC}$	V
T <sub>amb</sub>	ambient temperature		-40	+25	+125	-40	+25	+125	°C
$\Delta t/\Delta V$	input transition rise and fall rate	$V_{CC} = 2.0 \text{ V}$	-	-	625	-	-	-	ns/V
		V <sub>CC</sub> = 4.5 V	-	1.67	139	-	1.67	139	ns/V
		$V_{CC} = 6.0 \text{ V}$	-	-	83	-	-	-	ns/V

<sup>[2]</sup> For SO14 package: P<sub>tot</sub> derates linearly with 8 mW/K above 70 °C.
For TSSOP14 packages: P<sub>tot</sub> derates linearly with 5.5 mW/K above 60 °C.
For DHVQFN14 packages: P<sub>tot</sub> derates linearly with 4.5 mW/K above 60 °C.

### 9. Static characteristics

Table 6. Static characteristics

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		25 °C		-40 °C 1	to +85 °C	-40 °C to +125 °C		Unit
			Min	Тур	Max	Min	Max	Min	Max	
74HC00-	-Q100		'				'			
$V_{IH}$	HIGH-level	V <sub>CC</sub> = 2.0 V	-	1.2	-	1.5	-	1.5	-	V
	input voltage	V <sub>CC</sub> = 4.5 V	-	2.4	-	3.15	-	3.15	-	V
		V <sub>CC</sub> = 6.0 V	-	3.2	-	4.2	-	4.2	-	V
$V_{IL}$	LOW-level	V <sub>CC</sub> = 2.0 V	-	0.8	-	-	0.5	-	0.5	V
	input voltage	V <sub>CC</sub> = 4.5 V	-	2.1	-	-	1.35	-	1.35	V
	$V_{CC} = 6.0 \text{ V}$	-	2.8	-	-	1.8	-	1.8	V	
V <sub>OH</sub> HIGH-level		$V_I = V_{IH}$ or $V_{IL}$								
	output voltage	$I_O = -20 \mu A; V_{CC} = 2.0 V$	-	2.0	-	1.9	-	1.9	-	V
		$I_O = -20 \mu A; V_{CC} = 4.5 V$	-	4.5	-	4.4	-	4.4	-	V
		$I_O = -20 \mu A; V_{CC} = 6.0 V$	-	6.0	-	5.9	-	5.9	-	V
		$I_{O} = -4.0 \text{ mA}; V_{CC} = 4.5 \text{ V}$	-	4.32	-	3.84	-	3.7	-	V
		$I_{O} = -5.2 \text{ mA}; V_{CC} = 6.0 \text{ V}$	-	5.81	-	5.34	-	5.2	-	V
$V_{OL}$	LOW-level	$V_I = V_{IH}$ or $V_{IL}$								
	output voltage	$I_{O}$ = 20 $\mu$ A; $V_{CC}$ = 2.0 $V$	-	0	-	-	0.1	-	0.1	V
		$I_O$ = 20 $\mu$ A; $V_{CC}$ = 4.5 $V$	-	0	-	-	0.1	-	0.1	V
		$I_O = 20 \mu A; V_{CC} = 6.0 V$	-	0	-	-	0.1	-	0.1	V
		$I_{O} = 4.0 \text{ mA}; V_{CC} = 4.5 \text{ V}$	-	0.15	-	-	0.33	-	0.4	V
		$I_O = 5.2 \text{ mA}; V_{CC} = 6.0 \text{ V}$	-	0.16	-	-	0.33	-	0.4	V
l <sub>l</sub>	input leakage current	$V_I = V_{CC}$ or GND; $V_{CC} = 6.0 \text{ V}$	-	-	-	-	±1	-	±1	μΑ
I <sub>CC</sub>	supply current	$V_I = V_{CC}$ or GND; $I_O = 0$ A; $V_{CC} = 6.0 \text{ V}$	-	-	-	-	20	-	40	μΑ
C <sub>I</sub>	input capacitance		-	3.5	-	-	-	-	-	pF

74HC\_HCT00\_Q100

 Table 6.
 Static characteristics ...continued

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		25 °C		-40 °C 1	to +85 °C	-40 °C to	+125 °C	Unit
			Min	Тур	Max	Min	Max	Min	Max	
<b>74HCT0</b>	0-Q100									
$V_{IH}$	HIGH-level input voltage	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	-	1.6	-	2.0	-	2.0	-	V
V <sub>IL</sub>	LOW-level input voltage	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	-	1.2	-	-	0.8	-	0.8	V
V <sub>OH</sub> HIGH-level		$V_I = V_{IH}$ or $V_{IL}$ ; $V_{CC} = 4.5 \text{ V}$								
	output voltage	$I_{O} = -20 \mu A$	-	4.5	-	4.4	-	4.4	-	V
		$I_{O} = -4.0 \text{ mA}$	-	4.32	-	3.84	-	3.7	-	V
V <sub>OL</sub> LOW-level		$V_I = V_{IH}$ or $V_{IL}$ ; $V_{CC} = 4.5 \text{ V}$								
	output voltage	$I_O = 20 \mu A; V_{CC} = 4.5 V$	-	0	-	-	0.1	-	0.1	V
		$I_O = 5.2 \text{ mA}; V_{CC} = 6.0 \text{ V}$	-	0.15	-	-	0.33	-	0.4	V
II	input leakage current	$V_I = V_{CC}$ or GND; $V_{CC} = 6.0 \text{ V}$	-	-	-	-	±1	-	±1	μΑ
I <sub>CC</sub>	supply current	$V_I = V_{CC}$ or GND; $I_O = 0$ A; $V_{CC} = 6.0 \text{ V}$	-	-	-	-	20	-	40	μΑ
Δl <sub>CC</sub>	additional supply current	per input pin; $\begin{aligned} &V_I = V_{CC} - 2.1 \text{ V; } I_O = 0 \text{ A;} \\ &\text{other inputs at } V_{CC} \text{ or GND;} \\ &V_{CC} = 4.5 \text{ V to } 5.5 \text{ V} \end{aligned}$	-	150	-	-	675	-	735	μА
Cı	input capacitance		-	3.5	-	-	-	-	-	pF

# 10. Dynamic characteristics

Table 7. Dynamic characteristics

 $GND = 0 \ V; \ C_L = 50 \ pF;$  for load circuit see <u>Figure 7</u>.

Symbol	Parameter	Conditions			25 °C		-40 °C to +125 °C		Unit
				Min	Тур	Max	Max (85 °C)	Max (125 °C)	
74HC00-	Q100								
t <sub>pd</sub>	propagation delay	nA, nB to nY; see Figure 6	<u>[1]</u>						
		V <sub>CC</sub> = 2.0 V		-	25	-	115	135	ns
		V <sub>CC</sub> = 4.5 V		-	9	-	23	27	ns
		$V_{CC} = 5.0 \text{ V}; C_L = 15 \text{ pF}$		-	7	-	-	-	ns
		$V_{CC} = 6.0 \text{ V}$		-	7	-	20	23	ns
t <sub>t</sub>	transition time	see Figure 6	[2]						
		V <sub>CC</sub> = 2.0 V		-	19	-	95	110	ns
		V <sub>CC</sub> = 4.5 V		-	7	-	19	22	ns
		V <sub>CC</sub> = 6.0 V		-	6	-	16	19	ns
$C_{PD}$	power dissipation capacitance	per package; $V_I = GND$ to $V_{CC}$	[3]	-	22	-	-	-	pF

74HC\_HCT00\_Q100

All information provided in this document is subject to legal disclaimers.

**Table 7. Dynamic characteristics** ...continued GND = 0 V;  $C_L = 50$  pF; for load circuit see <u>Figure 7</u>.

Symbol	Parameter	Conditions		25 °C			–40 °C to	Unit	
				Min	Тур	Max	Max (85 °C)	Max (125 °C)	
74HCT0	0-Q100	'	·			•			
t <sub>pd</sub>	propagation delay	nA, nB to nY; see Figure 6	<u>[1]</u>						
		$V_{CC} = 4.5 \text{ V}$		-	12	-	24	29	ns
		$V_{CC} = 5.0 \text{ V}; C_L = 15 \text{ pF}$		-	10	-	-	-	ns
t <sub>t</sub>	transition time	V <sub>CC</sub> = 4.5 V; see <u>Figure 6</u>	[2]	-	-	-	29	22	ns
$C_{PD}$	power dissipation capacitance	per package; V <sub>I</sub> = GND to V <sub>CC</sub> – 1.5 V	<u>[3]</u>	-	22	-	-	-	pF

- [1]  $t_{pd}$  is the same as  $t_{PHL}$  and  $t_{PLH}$ .
- [2]  $t_t$  is the same as  $t_{THL}$  and  $t_{TLH}$ .
- [3]  $C_{PD}$  is used to determine the dynamic power dissipation ( $P_D$  in  $\mu W$ ):

 $P_D = C_{PD} \times V_{CC}^2 \times f_i \times N + \sum (C_L \times V_{CC}^2 \times f_o)$  where:

 $f_i$  = input frequency in MHz;

f<sub>o</sub> = output frequency in MHz;

C<sub>L</sub> = output load capacitance in pF;

V<sub>CC</sub> = supply voltage in V;

N = number of inputs switching;

 $\sum$  (C<sub>L</sub> × V<sub>CC</sub><sup>2</sup> × f<sub>o</sub>) = sum of outputs.

### 11. Waveforms

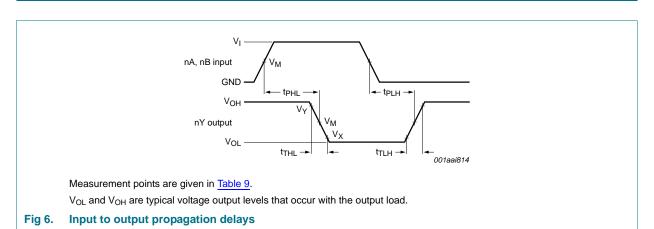
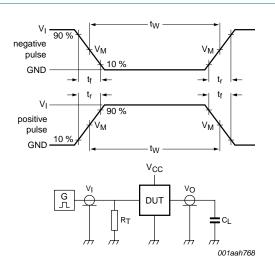


Table 8. Measurement points

Туре	Input	Output					
	V <sub>M</sub>	V <sub>M</sub>	V <sub>X</sub>	V <sub>Y</sub>			
74HC00-Q100	0.5V <sub>CC</sub>	0.5V <sub>CC</sub>	0.1V <sub>CC</sub>	0.9V <sub>CC</sub>			
74HCT00-Q100	1.3 V	1.3 V	0.1V <sub>CC</sub>	0.9V <sub>CC</sub>			

74HC\_HCT00\_Q100

All information provided in this document is subject to legal disclaimers.



Test data is given in Table 9.

Definitions test circuit:

 $R_T$  = termination resistance should be equal to output impedance  $Z_o$  of the pulse generator.

 $C_L$  = load capacitance including jig and probe capacitance.

Fig 7. Test circuit for measuring switching times

Table 9. Test data

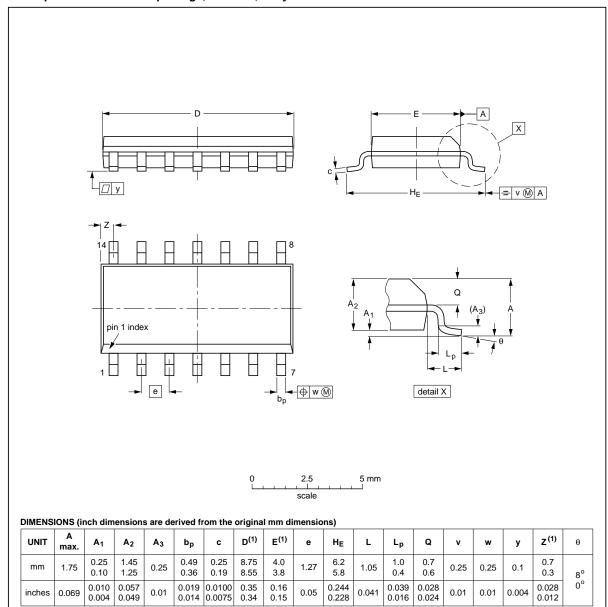
Туре	Input		Load	Test	
	VI	t <sub>r</sub> , t <sub>f</sub>	C <sub>L</sub>		
74HC00-Q100	$V_{CC}$	6.0 ns	15 pF, 50 pF	t <sub>PLH</sub> , t <sub>PHL</sub>	
74HCT00-Q100	3.0 V	6.0 ns	15 pF, 50 pF	t <sub>PLH</sub> , t <sub>PHL</sub>	

Downloaded from Elcodis.com electronic components distributor

# 12. Package outline

SO14: plastic small outline package; 14 leads; body width 3.9 mm

SOT108-1



### Note

1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.

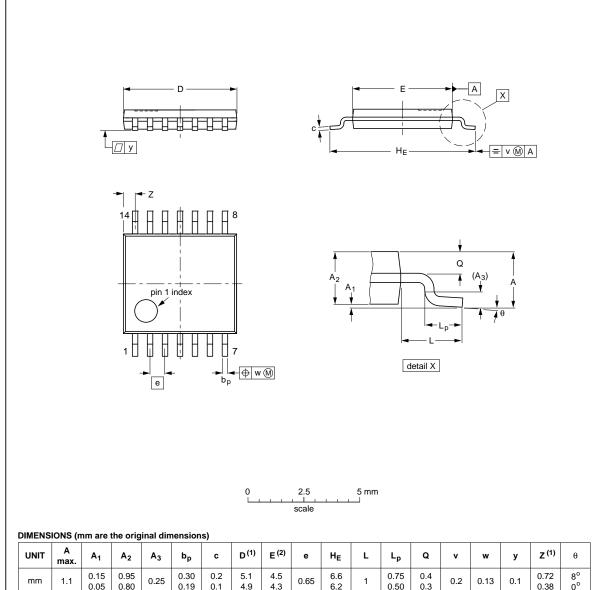
OUTLINE VERSION		REFER	EUROPEAN	ISSUE DATE	
	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT108-1	076E06	MS-012			<del>99-12-27</del> 03-02-19

Fig 8. Package outline SOT108-1 (SO14)

74HC\_HCT00\_Q100 All information provided in this document is subject to legal disclaimers.

TSSOP14: plastic thin shrink small outline package; 14 leads; body width 4.4 mm

SOT402-1



UNIT	A max.	A <sub>1</sub>	A <sub>2</sub>	A <sub>3</sub>	bp	С	D <sup>(1)</sup>	E (2)	е	HE	L	Lp	Q	v	w	у	Z <sup>(1)</sup>	θ	
mm	1.1	0.15 0.05	0.95 0.80	0.25	0.30 0.19	0.2 0.1	5.1 4.9	4.5 4.3	0.65	6.6 6.2	1	0.75 0.50	0.4 0.3	0.2	0.13	0.1	0.72 0.38	8° 0°	

- 1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
- 2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE			
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE	
SOT402-1		MO-153				<del>99-12-27</del> 03-02-18	

Fig 9. Package outline SOT402-1 (TSSOP14)

74HC\_HCT00\_Q100 All information provided in this document is subject to legal disclaimers.

DHVQFN14: plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; 14 terminals; body 2.5 x 3 x 0.85 mm SOT762-1

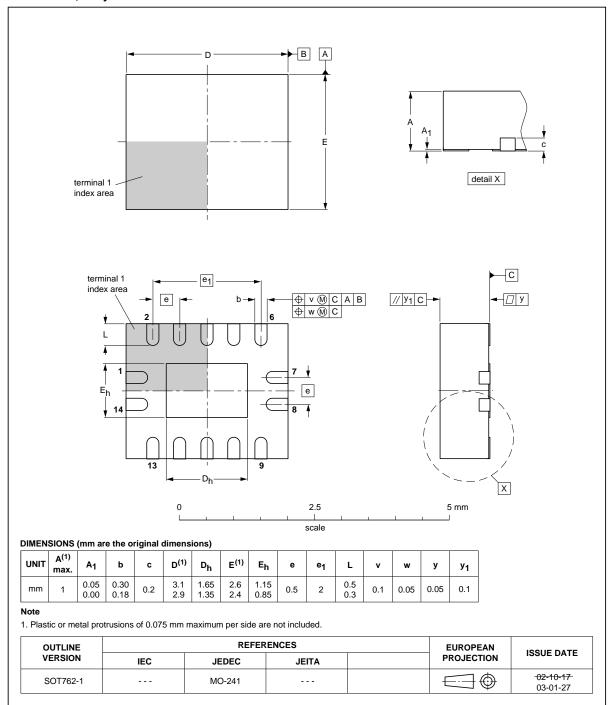


Fig 10. Package outline SOT762-1 (DHVQFN14)

74HC\_HCT00\_Q100 All information provided in this document is subject to legal disclaimers. © NXP B.V. 2012. All rights reserved.

Product data sheet Rev. 1 — 12 July 2012 11 of 15

### 13. Abbreviations

### Table 10. Abbreviations

Acronym	Description			
CMOS	Complementary Metal-Oxide Semiconductor			
DUT	Device Under Test			
ESD	ElectroStatic Discharge			
НВМ	Human Body Model			
LSTTL	Low-power Schottky Transistor-Transistor Logic			
MM	Machine Model			
TTL	Transistor-Transistor Logic			
MIL	Military			

# 14. Revision history

### Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
74HC_HCT00_Q100 v.1	20120712	Product data sheet	-	-

## 15. Legal information

### 15.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

### 15.2 Definitions

**Draft** — The document is a draft version only. The content is still under internal review and subject to formal approval, which may result in modifications or additions. NXP Semiconductors does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

Short data sheet — A short data sheet is an extract from a full data sheet with the same product type number(s) and title. A short data sheet is intended for quick reference only and should not be relied upon to contain detailed and full information. For detailed and full information see the relevant full data sheet, which is available on request via the local NXP Semiconductors sales office. In case of any inconsistency or conflict with the short data sheet, the full data sheet shall prevail.

Product specification — The information and data provided in a Product data sheet shall define the specification of the product as agreed between NXP Semiconductors and its customer, unless NXP Semiconductors and customer have explicitly agreed otherwise in writing. In no event however, shall an agreement be valid in which the NXP Semiconductors product is deemed to offer functions and qualities beyond those described in the Product data sheet.

### 15.3 Disclaimers

Limited warranty and liability — Information in this document is believed to be accurate and reliable. However, NXP Semiconductors does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information. NXP Semiconductors takes no responsibility for the content in this document if provided by an information source outside of NXP Semiconductors.

In no event shall NXP Semiconductors be liable for any indirect, incidental, punitive, special or consequential damages (including - without limitation - lost profits, lost savings, business interruption, costs related to the removal or replacement of any products or rework charges) whether or not such damages are based on tort (including negligence), warranty, breach of contract or any other legal theory.

Notwithstanding any damages that customer might incur for any reason whatsoever, NXP Semiconductors' aggregate and cumulative liability towards customer for the products described herein shall be limited in accordance with the *Terms and conditions of commercial sale* of NXP Semiconductors.

Right to make changes — NXP Semiconductors reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

Suitability for use in automotive applications — This NXP

Semiconductors product has been qualified for use in automotive applications. Unless otherwise agreed in writing, the product is not designed, authorized or warranted to be suitable for use in life support, life-critical or safety-critical systems or equipment, nor in applications where failure or malfunction of an NXP Semiconductors product can reasonably be expected to result in personal injury, death or severe property or environmental damage. NXP Semiconductors and its suppliers accept no liability for inclusion and/or use of NXP Semiconductors products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk

**Applications** — Applications that are described herein for any of these products are for illustrative purposes only. NXP Semiconductors makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

Customers are responsible for the design and operation of their applications and products using NXP Semiconductors products, and NXP Semiconductors accepts no liability for any assistance with applications or customer product design. It is customer's sole responsibility to determine whether the NXP Semiconductors product is suitable and fit for the customer's applications and products planned, as well as for the planned application and use of customer's third party customer(s). Customers should provide appropriate design and operating safeguards to minimize the risks associated with their applications and products.

NXP Semiconductors does not accept any liability related to any default, damage, costs or problem which is based on any weakness or default in the customer's applications or products, or the application or use by customer's third party customer(s). Customer is responsible for doing all necessary testing for the customer's applications and products using NXP Semiconductors products in order to avoid a default of the applications and the products or of the application or use by customer's third party customer(s). NXP does not accept any liability in this respect.

Limiting values — Stress above one or more limiting values (as defined in the Absolute Maximum Ratings System of IEC 60134) will cause permanent damage to the device. Limiting values are stress ratings only and (proper) operation of the device at these or any other conditions above those given in the Recommended operating conditions section (if present) or the Characteristics sections of this document is not warranted. Constant or repeated exposure to limiting values will permanently and irreversibly affect the quality and reliability of the device.

Terms and conditions of commercial sale — NXP Semiconductors products are sold subject to the general terms and conditions of commercial sale, as published at <a href="http://www.nxp.com/profile/terms">http://www.nxp.com/profile/terms</a>, unless otherwise agreed in a valid written individual agreement. In case an individual agreement is concluded only the terms and conditions of the respective agreement shall apply. NXP Semiconductors hereby expressly objects to applying the customer's general terms and conditions with regard to the purchase of NXP Semiconductors products by customer.

74HC\_HCT00\_Q100

All information provided in this document is subject to legal disclaimers.

# 74HC00-Q100; 74HCT00-Q100

**Quad 2-input NAND gate** 

No offer to sell or license — Nothing in this document may be interpreted or construed as an offer to sell products that is open for acceptance or the grant, conveyance or implication of any license under any copyrights, patents or other industrial or intellectual property rights.

**Export control** — This document as well as the item(s) described herein may be subject to export control regulations. Export might require a prior authorization from competent authorities.

**Translations** — A non-English (translated) version of a document is for reference only. The English version shall prevail in case of any discrepancy between the translated and English versions.

### 15.4 Trademarks

Notice: All referenced brands, product names, service names and trademarks are the property of their respective owners.

### 16. Contact information

For more information, please visit: http://www.nxp.com

For sales office addresses, please send an email to: <a href="mailto:salesaddresses@nxp.com">salesaddresses@nxp.com</a>

74HC\_HCT00\_Q100

All information provided in this document is subject to legal disclaimers.

© NXP B.V. 2012. All rights reserved.

**Product data sheet** 

# 74HC00-Q100; 74HCT00-Q100

### **NXP Semiconductors**

**Quad 2-input NAND gate** 

## 17. Contents

1	General description
2	Features and benefits
3	Ordering information
4	Functional diagram 2
5	Pinning information 3
5.1	Pinning
5.2	Pin description
6	Functional description 3
7	Limiting values4
8	Recommended operating conditions 4
9	Static characteristics 5
10	Dynamic characteristics 6
11	Waveforms
12	Package outline
13	Abbreviations
14	Revision history 12
15	Legal information
15.1	Data sheet status
15.2	Definitions
15.3	Disclaimers
15.4	Trademarks14
16	Contact information 14
17	Contents 15

Please be aware that important notices concerning this document and the product(s) described herein, have been included in section 'Legal information'.

© NXP B.V. 2012.

All rights reserved.

For more information, please visit: http://www.nxp.com For sales office addresses, please send an email to: salesaddresses@nxp.com

Date of release: 12 July 2012
Document identifier: 74HC\_HCT00\_Q100